

Notice of References Cited		Application/Control No. 10/725,903	Applicant(s)/Patent Under Reexamination WIENEKE, BERNHARD	
		Examiner CHIA-WEI A. CHEN	Art Unit 2622	Page 1 of 1

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B US-5,610,703	03-1997	Raffel et al.	356/28
C	US-			
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J	US-			
K	US-			
L	US-			
M	US-			

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.